

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TANIZAKI, TETSUSHI	
		Examiner Cynthia Britt	Art Unit 2138	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,173,906	12-1992	Dreibelbis et al.	714/733
*	B	US-7,007,215	02-2006	Kinoshita et al.	714/745
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Testing Embedded Memories" by Chuck Plagmann Copyright 1997 Nelson Publishing Inc. <a href="http://www.evaluationengineering.com/archive/articles/1197mem.htm">http://www.evaluationengineering.com/archive/articles/1197mem.htm</a>
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.